## **60V N-Channel DTMOS**

### **FEATURES**

- Trench Power DTMOS technology
- Low R<sub>DS(ON)</sub>
- Low Gate Charge
- Optimized for fast-switching applications

#### **APPLICATIONS**

- Synchronous Rectification in DC/DC and AC/DC Converters
- Isolated DC/DC Converters in Telecom and Industrial

TO-252 G	G
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Device Marking and Package Information			
Device Package		Marking	
TSD10N06AT	TO-252	10N06AT	



<b>Absolute Maximum Ratings</b> $T_C = 25^{\circ}C$ , unless otherwise noted			
Parameter	Symbol	Value	Unit
Drain-Source Voltage (V <sub>GS</sub> = 0V)	V <sub>DSS</sub>	60	V
Continuous Drain Current	I <sub>D</sub>	45	Α
Pulsed Drain Current (note1)	I <sub>DM</sub>	180	Α
Gate-Source Voltage	V <sub>GSS</sub>	±20	>
Single Pulse Avalanche Energy (note2)	E <sub>AS</sub>	20	mJ
Avalanche Current (note1)	I <sub>AS</sub>	20	Α
Power Dissipation (T <sub>C</sub> = 25°C)	$P_{D}$	56.5	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55~+175	°C

Thermal Resistance			
Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	R <sub>thJC</sub>	2.1	000
Thermal Resistance, Junction-to-Ambient	R <sub>thJA</sub>	50	°C/W



Specifications T <sub>J</sub> = 25°C, unless otherwise noted							
Parameter	Symbol Test Conditions		Value			Unit	
			Min.	Тур.	Max.		
Static			1				
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_{D} = 250\mu A$	60			V	
Zero Gate Voltage Drain Current		$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 25^{\circ}C$			1		
Zero Gate Voltage Drain Gurrent	I <sub>DSS</sub>	$V_{DS} = 60V, V_{GS} = 0V, T_{J} = 150^{\circ}C$			100	μA	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{GS} = \pm 20V$			±100	nA	
Gate-Source Threshold Voltage	$V_{\rm GS(th)}$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.1		2.5	V	
Drain Course On Registeres (Note2)	D	$V_{GS} = 10V, I_D = 20A$		12	15	0	
Drain-Source On-Resistance (Note3)	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 18A		15	19	mΩ	
Forward Transconductance (Note3)	g <sub>fs</sub>	$V_{DS} = 5V, I_{D} = 20A$		100		S	
Dynamic				•			
Input Capacitance	C <sub>iss</sub>	V 0V		1134		pF	
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0V,$ $V_{DS} = 30V,$		123			
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0MHz		12			
T	Q <sub>g</sub> (10V)			21		nC	
Total Gate Charge	Q <sub>g</sub> (4.5V)	$V_{DD} = 30V, I_{D} = 20A,$		11			
Gate-Source Charge	$Q_{gs}$	$V_{GS} = 10V$		3.1			
Gate-Drain Charge	$Q_{gd}$			5.1			
Turn-on Delay Time	t <sub>d(on)</sub>			7			
Turn-on Rise Time	t <sub>r</sub>	$V_{DD} = 30V, I_{D} = 20A,$		3			
Turn-off Delay Time	t <sub>d(off)</sub>	$R_G = 3\Omega$		20		ns	
Turn-off Fall Time	t <sub>f</sub>			3			
Drain-Source Body Diode Characteristics							
Continuous Body Diode Current	I <sub>S</sub>				30		
Pulsed Diode Forward Current	I <sub>SM</sub>	$T_{\rm C} = 25^{\rm o}{\rm C}$			90	Α	
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25^{\circ}C$ , $I_{SD} = 1A$ , $V_{GS} = 0V$		0.72	1	V	
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 20A,		17		ns	
Reverse Recovery Charge	Q <sub>rr</sub>	$di_{F}/dt = 500A/\mu s$		60		nC	

#### Notes

- 1. Repetitive Rating: Pulse Width limited by maximum junction temperature
- 2.  $I_{AS}$  = 20A,  $V_{DD}$  = 50V,  $R_{G}$  = 25 $\Omega$ , Starting  $T_{J}$  = 25 $^{\circ}$ C
- 3. Pulse Test: Pulse Width  $\leq$  300 $\mu$ s, Duty Cycle  $\leq$  1%



## **Typical Characteristics** $T_J = 25^{\circ}C$ , unless otherwise noted

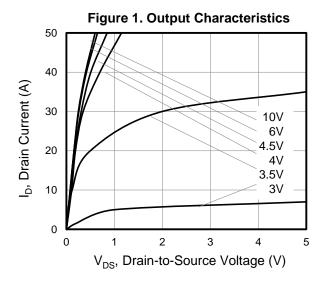


Figure 3. On-Resistance vs. Drain Current

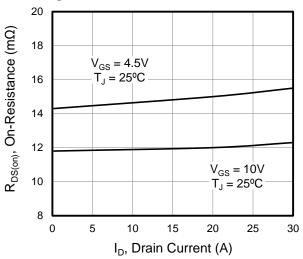


Figure 5. Gate Charge

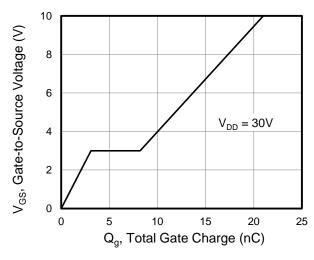


Figure 2. Transfer Characteristics

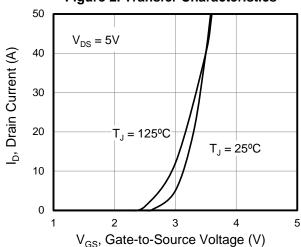


Figure 4. Capacitance

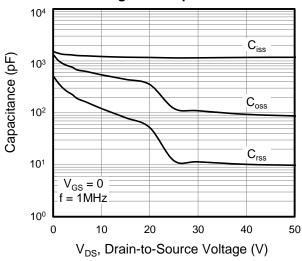
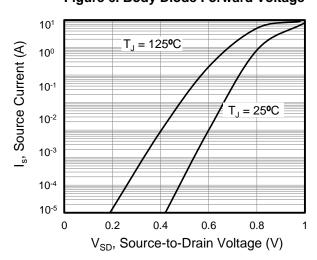


Figure 6. Body Diode Forward Voltage





## **Typical Characteristics** $T_J = 25^{\circ}\text{C}$ , unless otherwise noted

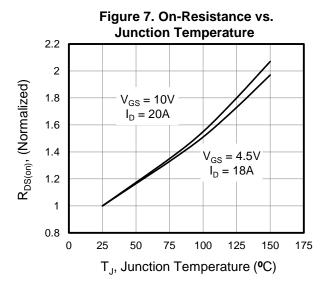
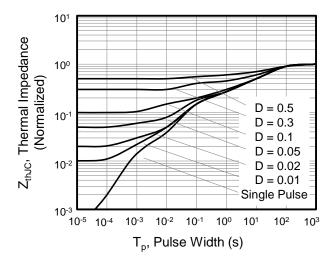


Figure 9. Transient Thermal Impedance



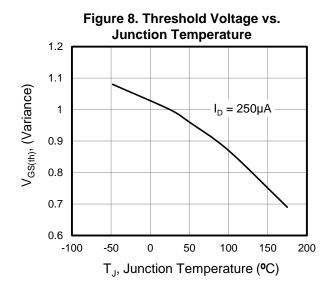




Figure A: Gate Charge Test Circuit and Waveform

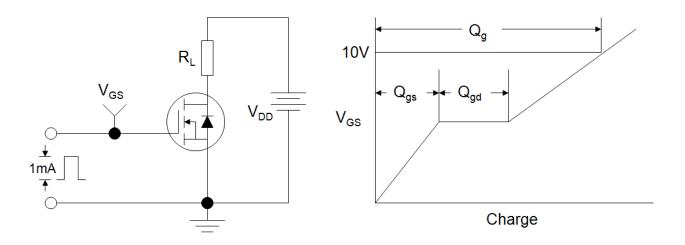


Figure B: Resistive Switching Test Circuit and Waveform

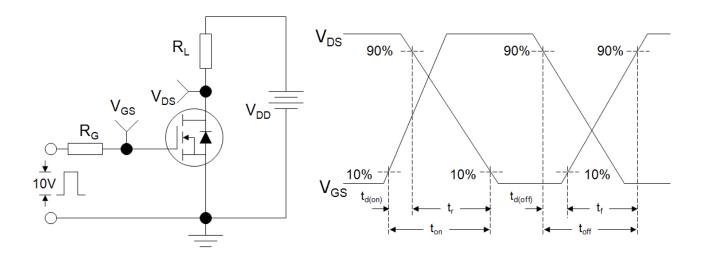
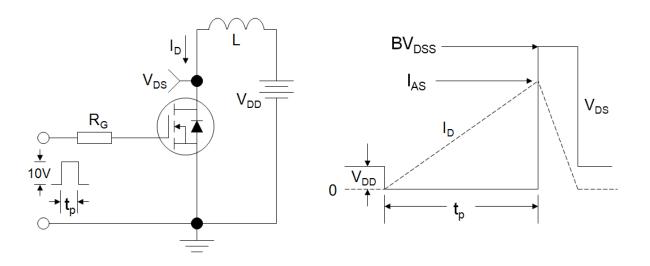
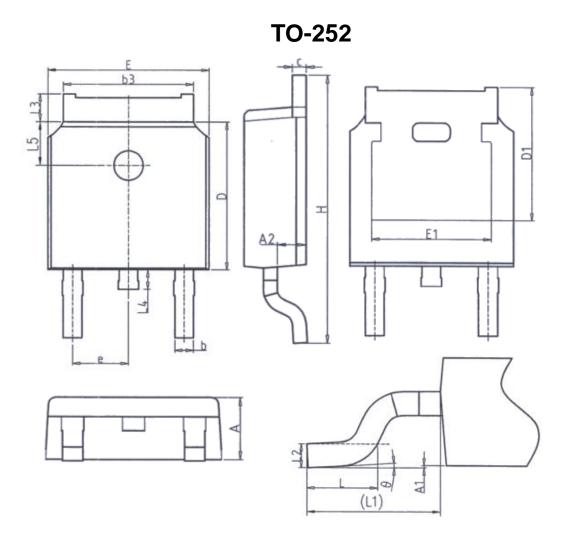


Figure C: Unclamped Inductive Switching Test Circuit and Waveform







Unit: mm		
Symbol	Min.	Max.
Α	2. 20	2. 40
A1	0.00	0. 20
A2	0. 97	1. 17
b	0. 68	0. 90
b3	5. 20	5. 50
С	0. 43	0. 63
D	5. 98	6. 22
D1	5. 30	DREF
E	6. 40	6. 80
E1	4. 63	_

Unit: mm			
Symbol	Min.	Max.	
е	2. 286BSC		
Н	9. 40	10.50	
L	1. 38	1. 75	
L1	2. 90REF		
L2	0. 51BSC		
L3	0.88	1. 28	
L4	_	1.00	
L5	1. 65	1. 95	
θ	0°	8°	



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